

Paper #18
Power to Inspect
09/30/03

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Fab Solutions, Inc.

Appl. No. : 09/702,831

Filed : November 1, 2000

For : SEMICONDUCTOR DEVICE TESTER

POWER TO INSPECT AND PHOTOCOPY

Commissioner for Patents
PO Box 1450
Alexandria, VA 22313-1450

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SEP 30 2003
TECHNOLOGY CENTER 2800

Sir:

The undersigned, who has authority to act for the assignee of the entire right and interest of the above identified application, hereby authorizes Michael Willens to inspect and photocopy the above-identified application.

Respectfully submitted,

Fab Solutions, Inc.
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